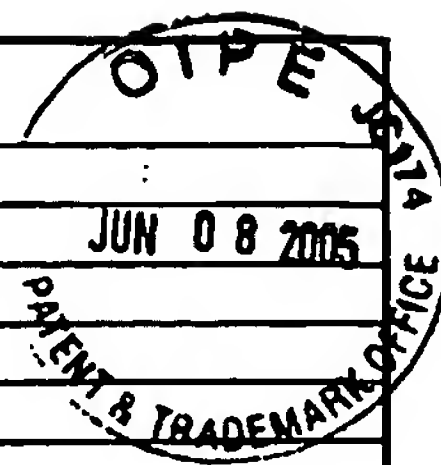


<p>IDS Form PTO/SB/08: Substitute for form 1449A/PTO</p> <p style="text-align: center;">INFORMATION DISCLOSURE STATEMENT BY APPLICANT</p> <p style="text-align: center;"><i>(Use as many sheets as necessary)</i></p>			<p>Complete if Known</p>	
			Application Number	10/031,073
			Filing Date	January 15, 2002
			First Named Inventor	Nobuya Kitaguchi et al.
			Art Unit	1743
			Examiner Name	Monique T. Cole
			Attorney Docket Number	7241-16
Sheet	1	of	2	



U.S. PATENTS AND PUBLISHED U.S. PATENT APPLICATIONS					
Examiner Initials	Cite No. ¹	Document Number	Issue or Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		Number-Kind Code ² (if known)			
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FOREIGN PATENT DOCUMENTS						
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NON PATENT LITERATURE DOCUMENTS			
Examiner Initials	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	Translation ⁶
MC		TAKEHIKO KITAMORI ET AL, "Thermal Lens Microscopy and Microchip Chemistry," Analytical Chemistry, February 1, 2004, pp. 53A-60A.	
/		KENJI UCHIYAMA ET AL., "Thermal Lens Microscope," Jpn. J. Appl. Phys. Vol. 39 (2000) pp. 5316-5322.	
/		MASAAKI HARADA ET AL., "Photothermal Microscopy with Excitation and Probe Beams Coaxial under the Microscope and Its Application to Microparticle Analysis," Anal. Chem. 1993, 65, 2938-2940.	

Examiner Signature	M. Cole	Date Considered	8/85
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EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.